

Product specification

1990 Nov 26

IC15 Data Handbook



PHILIPS

74F14

# Hex inverter Schmitt trigger

## FEATURE

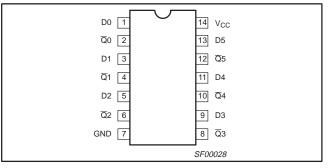
• Industrial temperature range available (-40°C to +85°C)

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F14	5.0ns	18mA

#### DESCRIPTION

The 74F14 contains six logic inverters which accept standard TTL input signals and provide standard TTL output levels. They are capable of transforming slowly changing input signals into sharply defined, jitter free output signals. In addition, they have greater noise margin than conventional inverters. Each circuit contains a Schmitt trigger followed by a Darlington level shifter and a phase splitter driving a TTL totem-pole output. The Schmitt trigger uses positive feedback to effectively speed-up slow input transitions, and provide different input threshold voltages for positive-going and negative-going input threshold (typically 800mV) is determined internally by resistor ratios and is insensitive to temperature and supply voltage variations.

#### **PIN CONFIGURATION**



## ORDERING INFORMATION

	c		
DESCRIPTION	$\begin{array}{l} \textbf{COMMERCIAL RANGE} \\ \textbf{V}_{CC} = 5V \pm 10\%, \ \textbf{T}_{amb} = 0^{\circ}\textbf{C} \ to \ \textbf{+70}^{\circ}\textbf{C} \end{array}$	INDUSTRIAL RANGE V <sub>CC</sub> = 5V $\pm$ 10%, T <sub>amb</sub> = -40°C to +85°C	PKG DWG #
14-pin plastic DIP	N74F14N	I74F14N	SOT27-1
14-pin plastic SO	N74F14D	I74F14D	SOT108-1

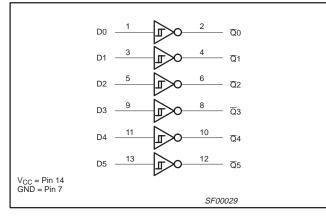
#### INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
Dn	Data inputs	1.0/1.0	20µA/0.6mA
Qn	Data output	50/33	1.0mA/20mA

#### NOTE:

1 One (1.0) FAST unit load is defined as: 20µA in the High state and 0.6mA in the Low state.

#### LOGIC DIAGRAM



### FUNCTION TABLE

INPUTS	OUTPUT
Dn	Qn
L	Н
Н	L

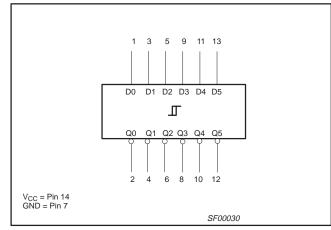
NOTES:

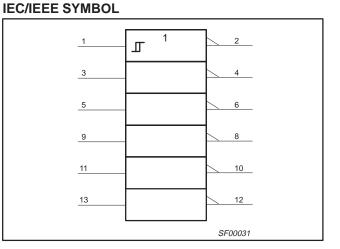
H = High voltage level

L = Low voltage level

74F14

### LOGIC SYMBOL





#### **ABSOLUTE MAXIMUM RATINGS**

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER		RATING	UNIT
V <sub>CC</sub>	Supply voltage		-0.5 to +7.0	V
V <sub>IN</sub>	Input voltage		-0.5 to +7.0	V
I <sub>IN</sub>	Input current		-30 to +5	mA
V <sub>OUT</sub>	Voltage applied to output in high output state		–0.5 to $V_{CC}$	V
I <sub>OUT</sub>	Current applied to output in low output state		40	mA
<b>-</b>		Commercial range	0 to +70	°C
T <sub>amb</sub>	Operating free-air temperature range	Industrial range	-40 to +85	°C
T <sub>stg</sub>	Storage temperature range	•	-65 to +150	°C

### **RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER		UNIT			
			MIN	NOM	MAX	
V <sub>CC</sub>	Supply voltage		4.5	5.0	5.5	V
V <sub>IH</sub>	High-level input voltage		2.0			V
VIL	Low-level input voltage				0.8	V
l <sub>lk</sub>	Input clamp current				-18	mA
I <sub>OH</sub>	High-level output current				-1	mA
I <sub>OL</sub>	Low-level output current				20	mA
-	Commercial range		0		+70	°C
T <sub>amb</sub>	Operating free air temperature range	Industrial range	-40		+85	°C

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#### DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER		TEST CONDITIO	NS <sup>1</sup>		LIMITS		UNIT
				MIN	TYP <sup>2</sup>	MAX		
V <sub>T+</sub>	Positive-going threshold		$V_{CC} = 5.0 V$		1.4	1.7	2.0	V
V <sub>T-</sub>	Negative-going threshold		V <sub>CC</sub> = 5.0V		0.7	0.9	1.1	V
$\Delta V_T$	Hysteresis (V <sub>T+</sub> – V <sub>T–</sub> )		V <sub>CC</sub> = 5.0V		0.4	0.8		V
V <sub>OH</sub>	High-level output voltage		$V_{CC} = MIN, V_I = V_{T-MIN},$	±10%V <sub>CC</sub>	2.5			V
			I <sub>OH</sub> = MAX	±5%V <sub>CC</sub>	2.7	3.4		V
V <sub>OL</sub>	Low-level output voltage		$V_{CC} = MIN, V_I = V_{T+MAX},$	±10%V <sub>CC</sub>		0.30	0.50	V
			I <sub>OL</sub> = MAX	±5%V <sub>CC</sub>		0.30	0.50	V
V <sub>IK</sub>	Input clamp voltage		$V_{CC} = MIN, I_I = I_{IK}$		-0.73	-1.2	V	
I <sub>T+</sub>	Input current at positive-going thre	shold	$V_{CC} = 5.0V, V_I = V_{T+}$		0		μA	
I <sub>T-</sub>	Input current at negative-going thr	eshold	$V_{CC} = 5.0V, V_I = V_{T-}$		-175		μA	
l <sub>l</sub>	Input current at maximum input vo	ltage	$V_{CC} = MAX, V_I = 7.0V$				100	μΑ
I <sub>IH</sub>	High-level input current		$V_{CC} = MAX, V_I = 2.7V$				20	μA
IIL	Low-level input current	$V_{CC} = MAX, V_I = 0.5V$				-0.6	mA	
I <sub>OS</sub>	Short-circuit output current <sup>3</sup>	V <sub>CC</sub> = MAX		-60		-150	mA	
I <sub>CC</sub>	Supply current (total)	I <sub>CCH</sub>	V <sub>CC</sub> = MAX	$V_{IN} = GND$		13	22	mA
		I <sub>CCL</sub>	$V_{CC} = MAX$	V <sub>IN</sub> = 4.5V		23	32	mA

NOTES:

1 For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

2

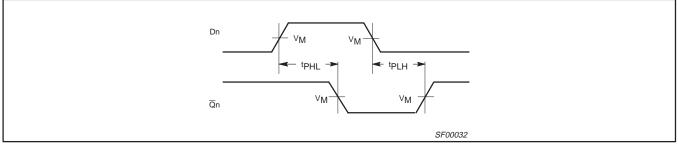
All typical values are at  $V_{CC} = 5V$ ,  $T_{amb} = 25^{\circ}C$ . Not more than one output should be shorted at a time. For testing  $I_{OS}$ , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting 3 of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests,  $I_{OS}$  tests should be performed last.

#### **AC ELECTRICAL CHARACTERISTICS**

			LIMITS							
SYMBOL	PARAMETER	TEST CONDITION	Ta	$V_{CC} = +5.0V$ $T_{amb} = +25^{\circ}C$ $C_{L} = 50pF, R_{L} = 500\Omega$		$\label{eq:CC} \begin{array}{l} V_{CC} = +5.0V \pm 10\% \\ T_{amb} = 0^\circ C \text{ to } +70^\circ C \\ C_L = 50 p \text{F}, \ R_L = 500 \Omega \end{array}$		V <sub>CC</sub> = +5. T <sub>amb</sub> = -40° C <sub>L</sub> = 50pF,	UNIT	
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay Dn to Qn	Waveform 1	4.0 3.5	6.5 5.0	8.5 6.5	4.0 3.5	9.5 7.0	3.0 3.5	10.5 9.0	ns

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#### **AC WAVEFORMS**

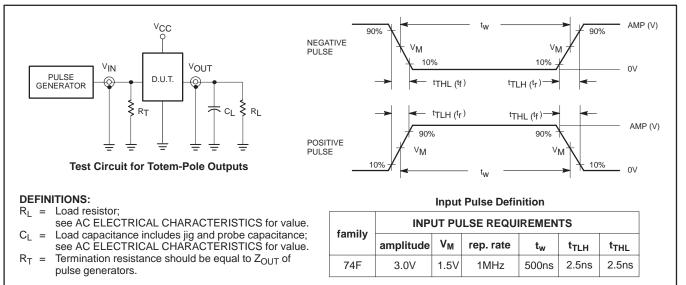




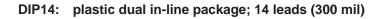
NOTE:

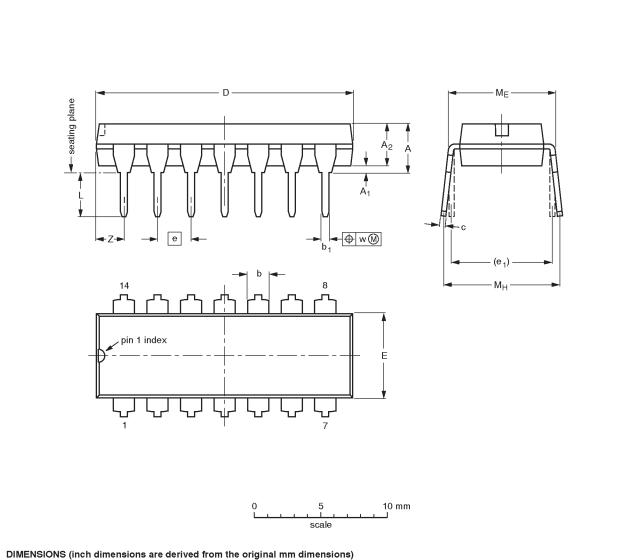
For all waveforms,  $V_M = 1.5V$ .

#### **TEST CIRCUIT AND WAVEFORMS**



SF00006





UNIT	A max.	A <sub>1</sub> min.	A <sub>2</sub> max.	b	b <sub>1</sub>	с	D <sup>(1)</sup>	E <sup>(1)</sup>	e	e <sub>1</sub>	L	M <sub>E</sub>	M <sub>H</sub>	w	Z <sup>(1)</sup> max.
mm	4.2	0.51	3.2	1.73 1.13	0.53 0.38	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.2
inches	0.17	0.020	0.13	0.068 0.044	0.021 0.015	0.014 0.009	0.77 0.73	0.26 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.087

#### Note

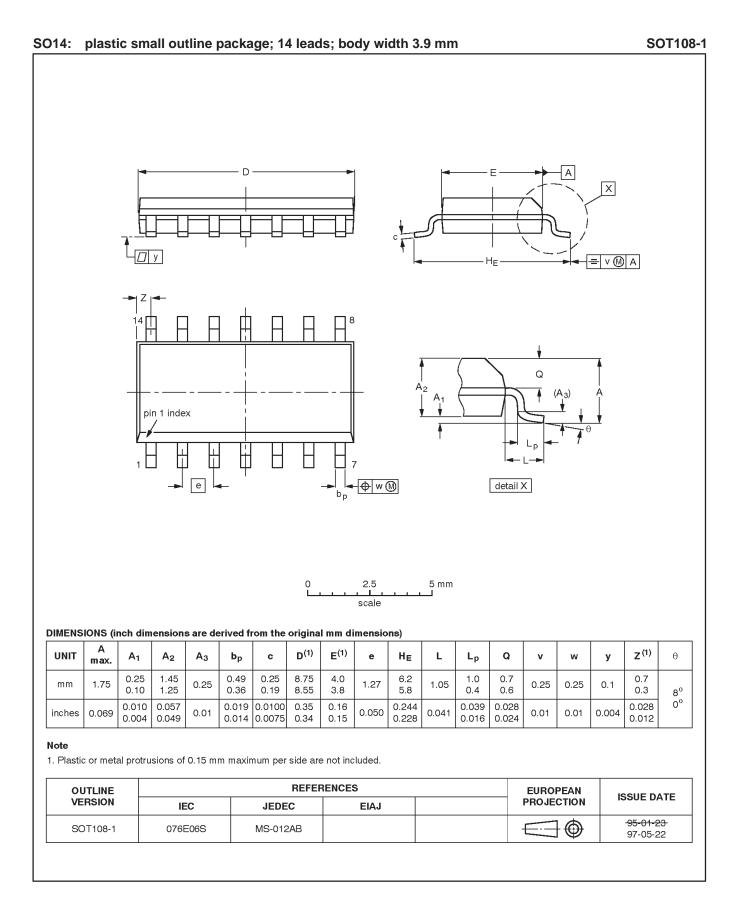
1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT27-1	050G04	MO-001AA				<del>-92-11-17</del> 95-03-11

### Product specification

SOT27-1

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#### Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
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[1] Please consult the most recently issued datasheet before initiating or completing a design.

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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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